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(12) **United States Design Patent** (10) **Patent No.:** **US D958,215 S**
Kojima et al. (45) **Date of Patent:** **** Jul. 19, 2022**

(54) **ELECTRON MICROSCOPE**

(56) **References Cited**

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(**) Term: **15 Years**

(57) **CLAIM**

(21) Appl. No.: **29/699,268**

The ornamental design for an electron microscope, as shown and described.

(22) Filed: **Jul. 24, 2019**

(30) **Foreign Application Priority Data**

DESCRIPTION

Jan. 29, 2019 (JP) 2019-001638

(51) **LOC (13) Cl.** **16-06**

(52) **U.S. Cl.**
USPC **D16/131**

(58) **Field of Classification Search**
USPC D10/70, 109.1, 109.2, 81; D16/134, 130, D16/131, 132, 135, 136, 137, 202–208, D16/245, 219; D24/120, 113, 118, 119, D24/121, 122, 124, 125, 128

CPC ... G01C 3/00; G01C 3/02; G01C 3/04; G01C 3/06; G01C 3/08; G01C 3/085; G01C 3/10; G01C 3/12; G01C 3/16; G01C 3/18; G01C 3/20; G01C 3/22; G01C 3/24; G01C 3/26; G01C 3/28; G01C 3/30; G01C 3/32; B60Q 1/04; B60Q 1/26; F21S 8/026; F21S 8/04; F21V 29/004; F21V 21/02; F21V 21/04; F21V 29/2212; F21Y 2101/02; G02B 27/026; G02B 23/16; G02B 2003/0093; G02B 3/04; H04J 11/00; H04J 13/00; E06B 9/24; G03B 17/02; C03B 2215/46

See application file for complete search history.

FIG. 1 is a front, top and right side perspective view of an electron microscope according to the design;

FIG. 2 is a front view thereof;

FIG. 3 is a right side view thereof;

FIG. 4 is a left side view thereof;

FIG. 5 is a rear view thereof;

FIG. 6 is a top plan view thereof;

FIG. 7 is a bottom plan view thereof;

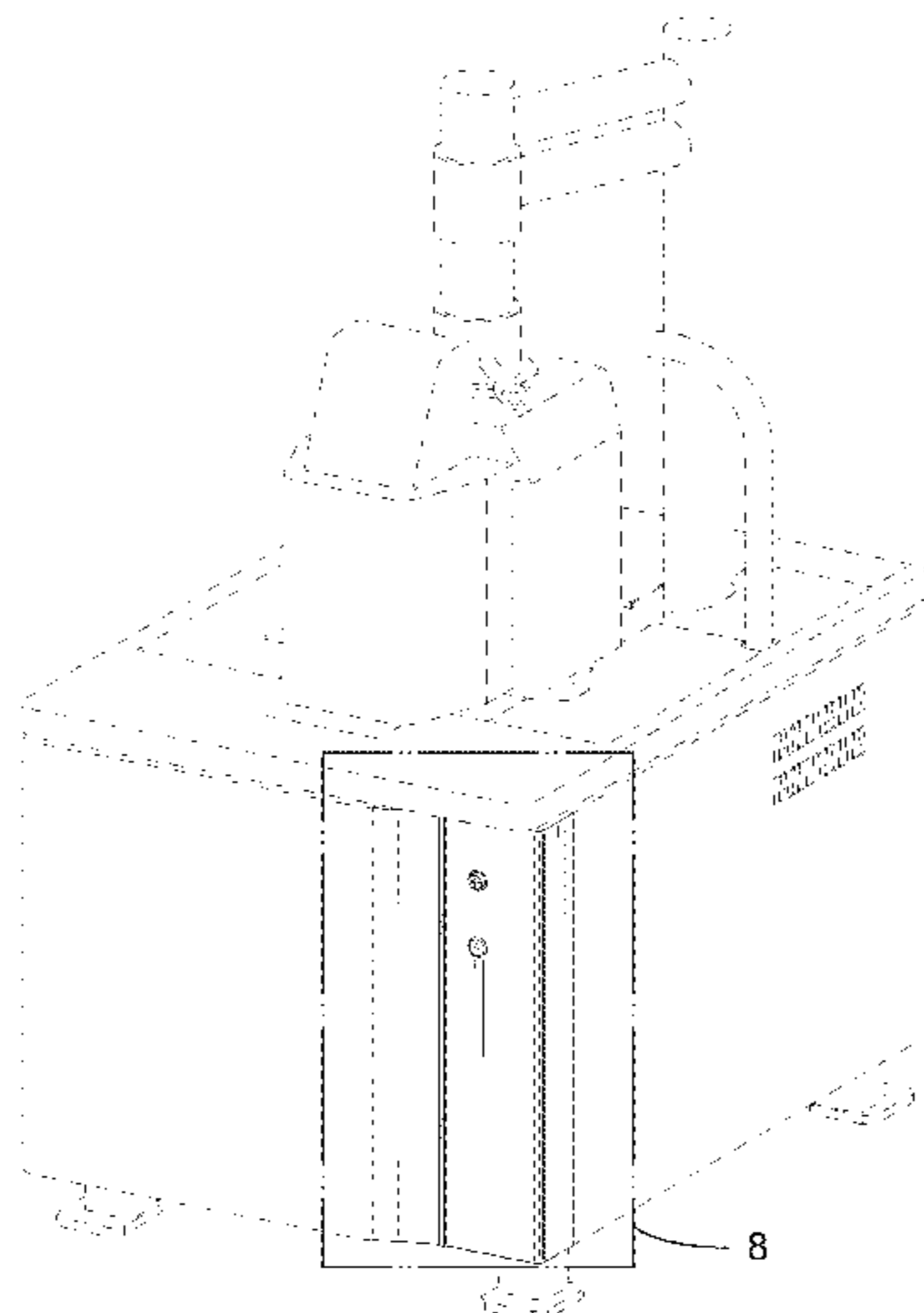
FIG. 8 is an enlarged view of the portion shown in BOX 8 in FIG. 1;

FIG. 9 is cross-sectional view taken along line 9-9 of FIG. 2; and,

FIG. 10 is an enlarged view of the portion shown in BOX 10 in FIG. 9.

The dashed broken lines in the drawings show portions of the electron microscope that form no part of the claimed design. The dot-dash broken lines in the drawings indicate boundaries of the claimed subject matter that form no part of the claimed design. The dot-dot-dash broken lines in the drawings indicate boundaries of the view indicators that form no part of the claimed design.

1 Claim, 10 Drawing Sheets



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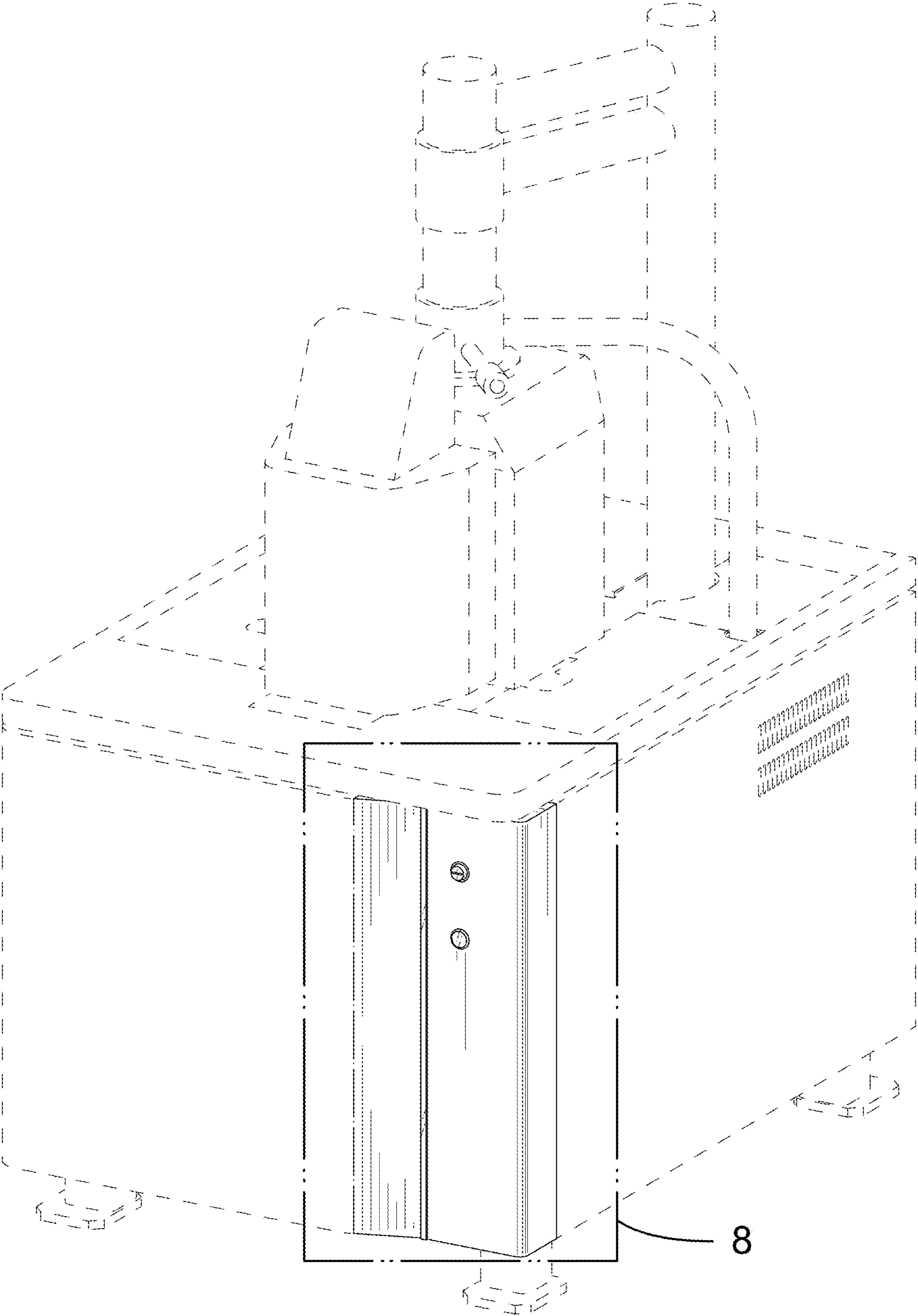


FIG. 1

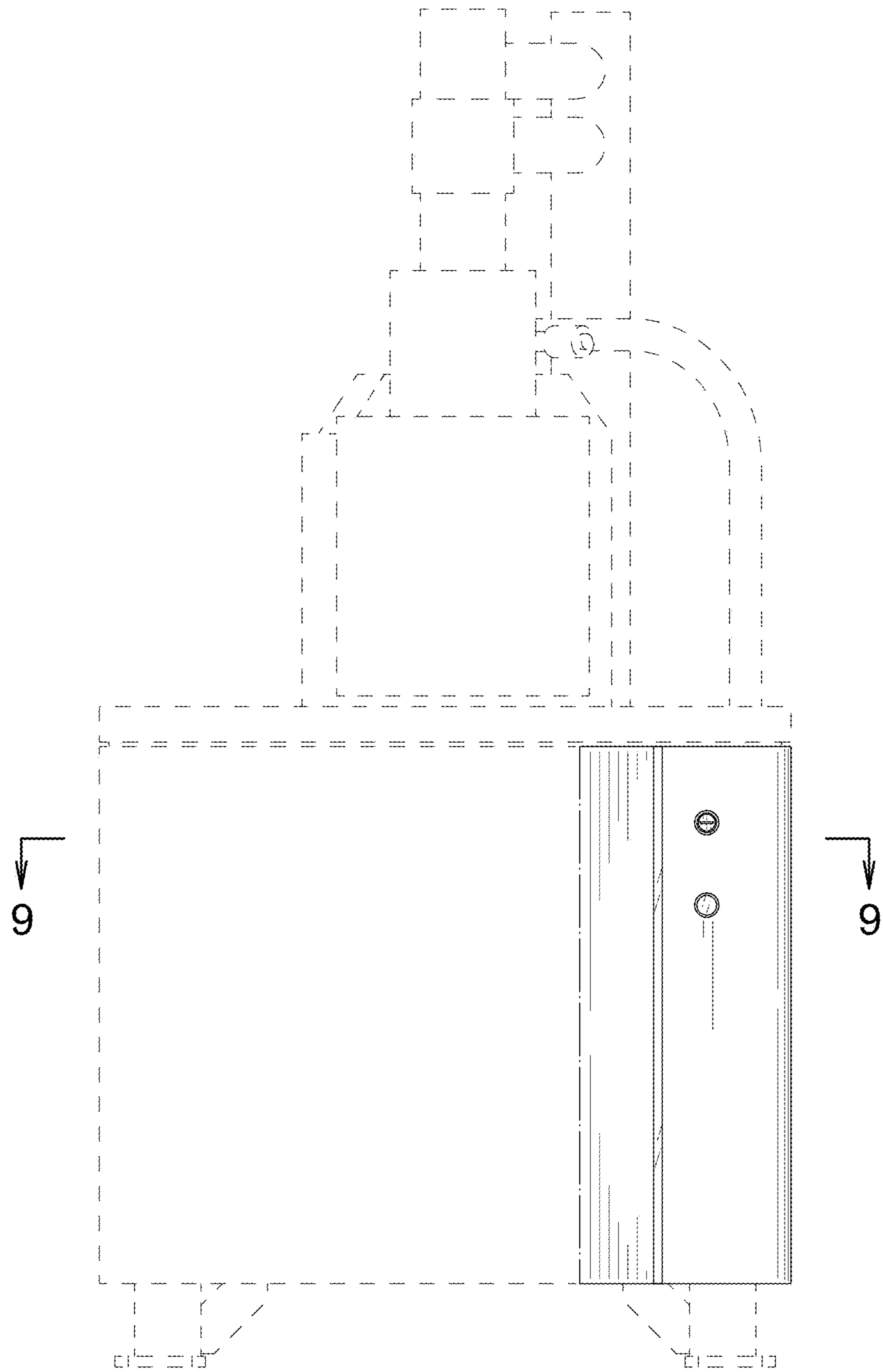


FIG. 2

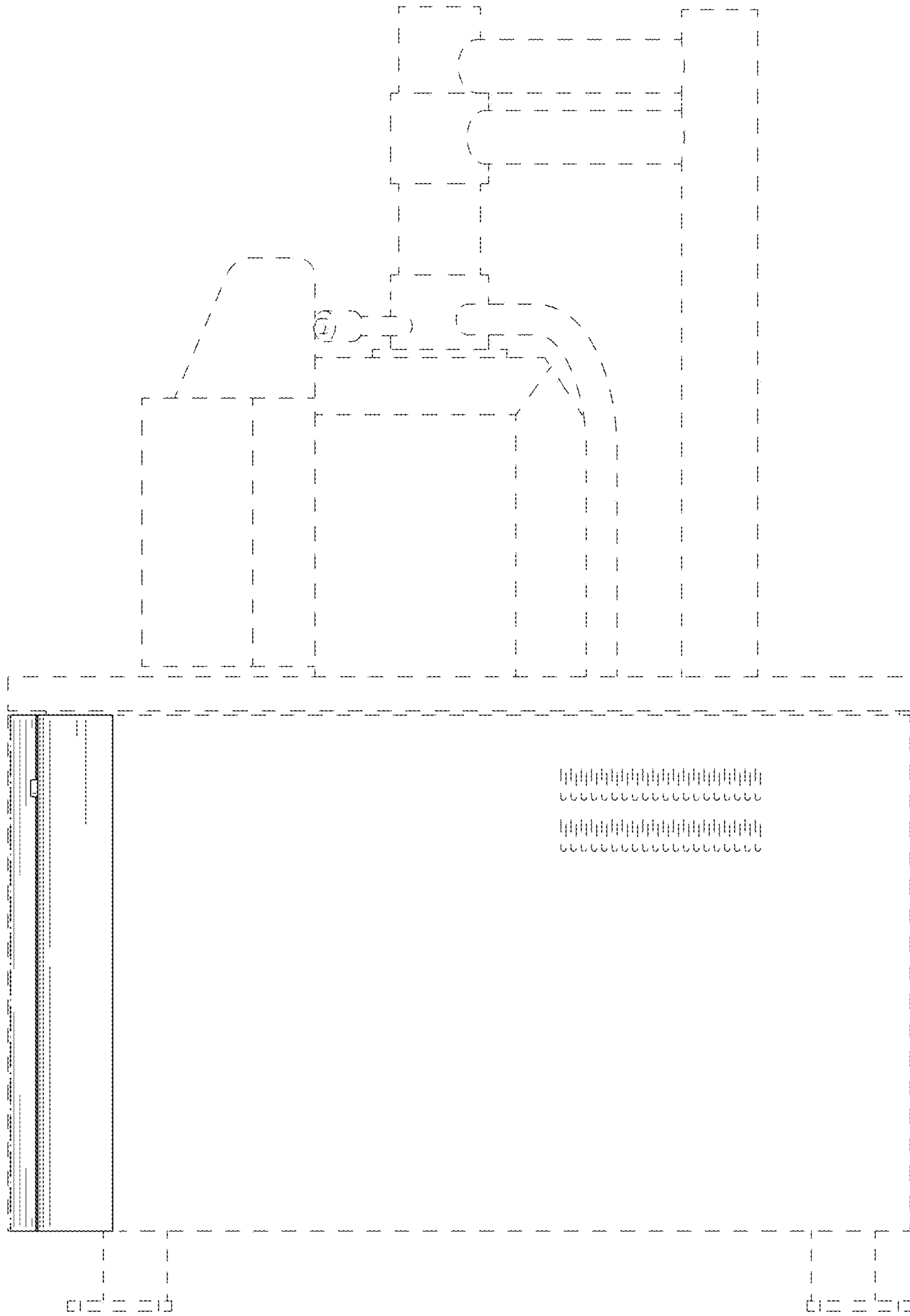


FIG. 3

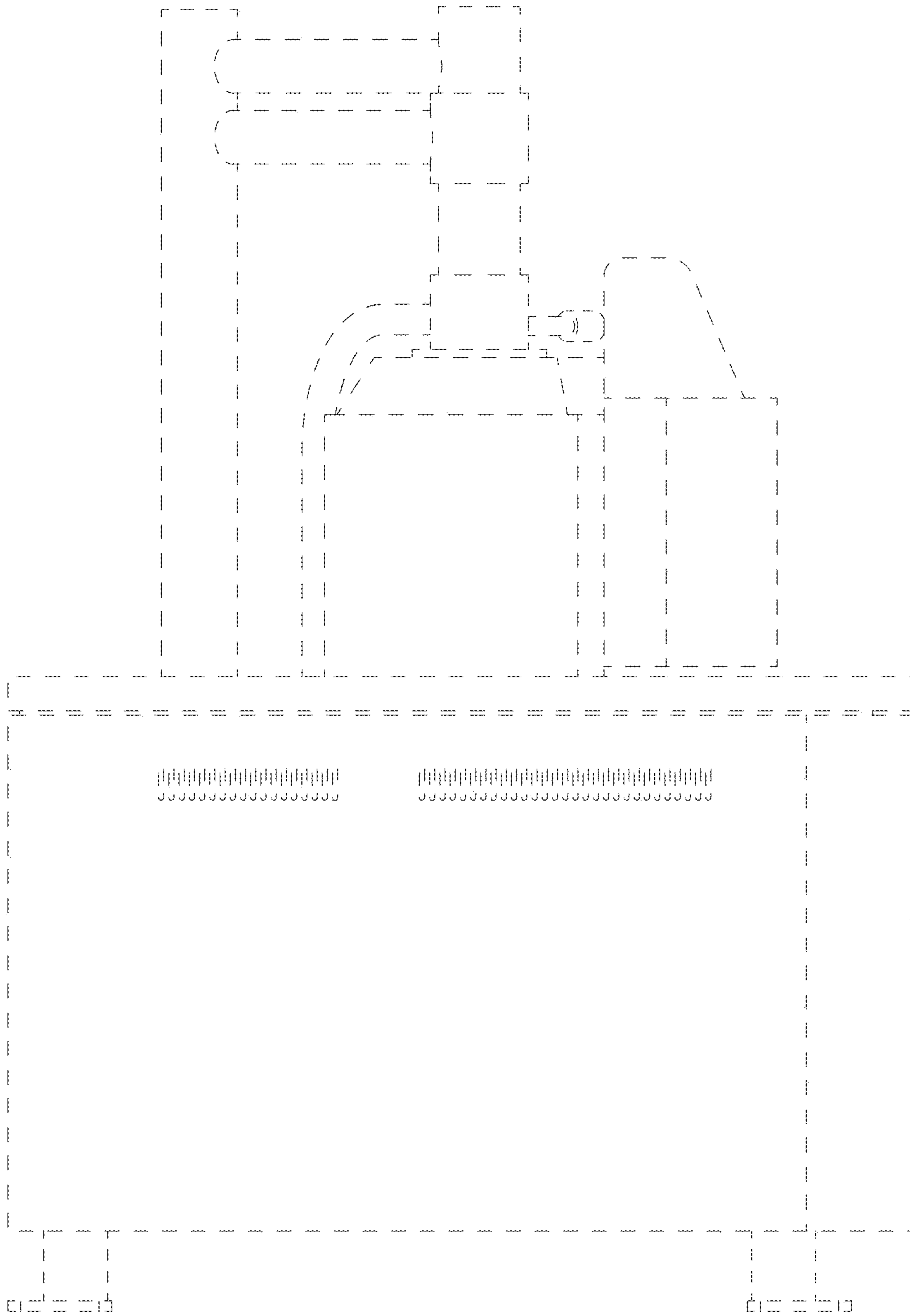


FIG. 4

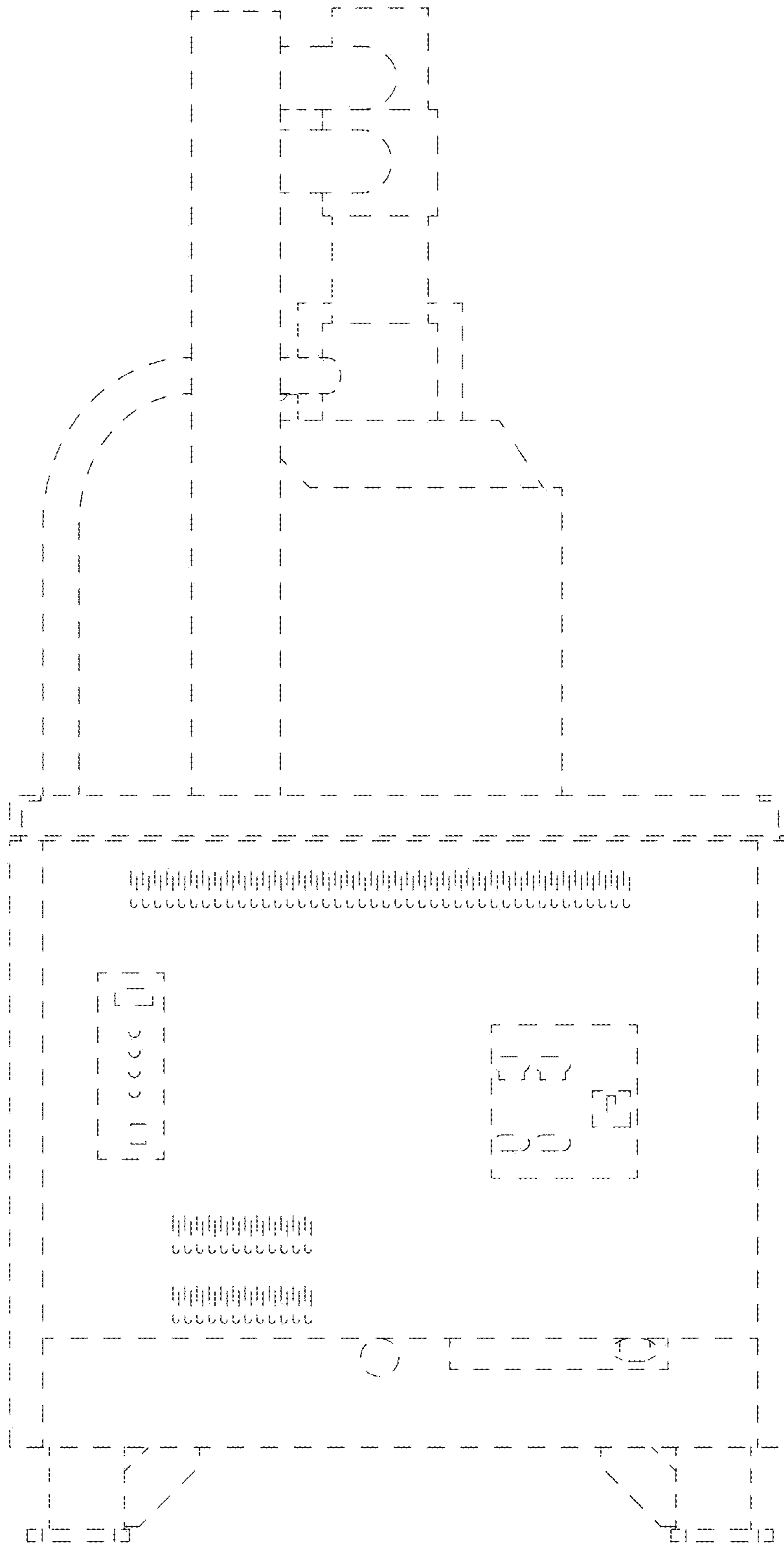


FIG. 5

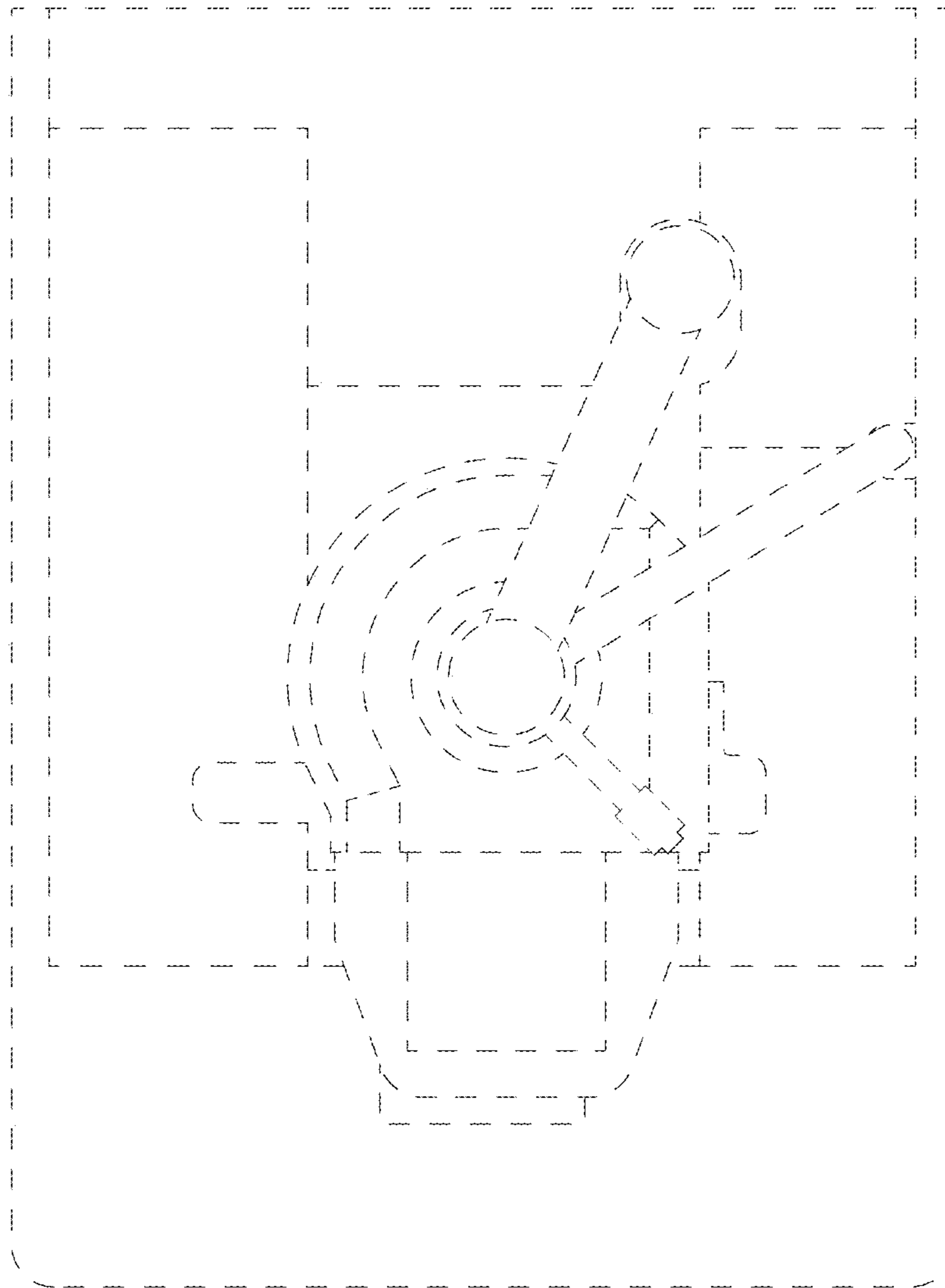


FIG. 6

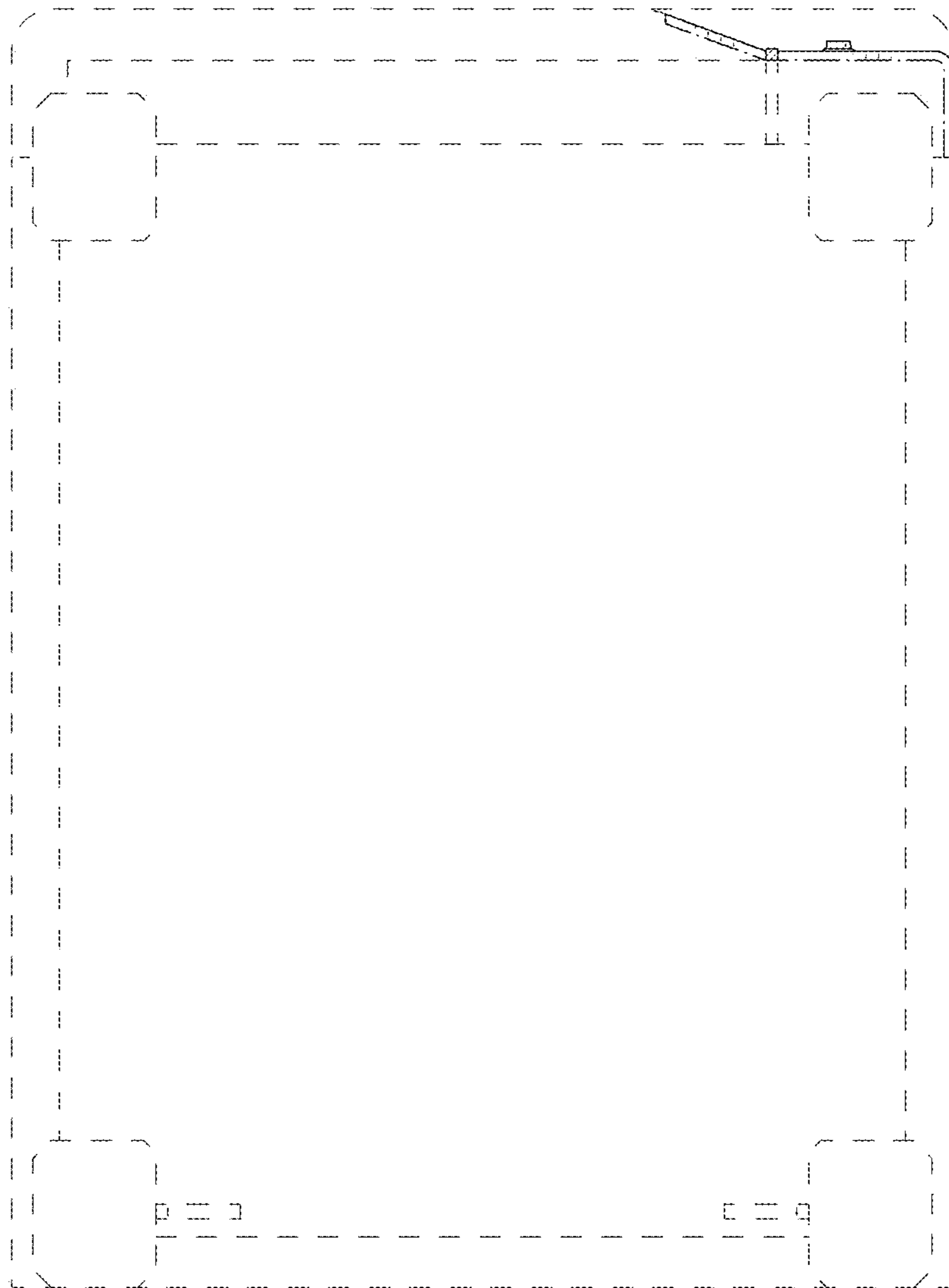


FIG. 7

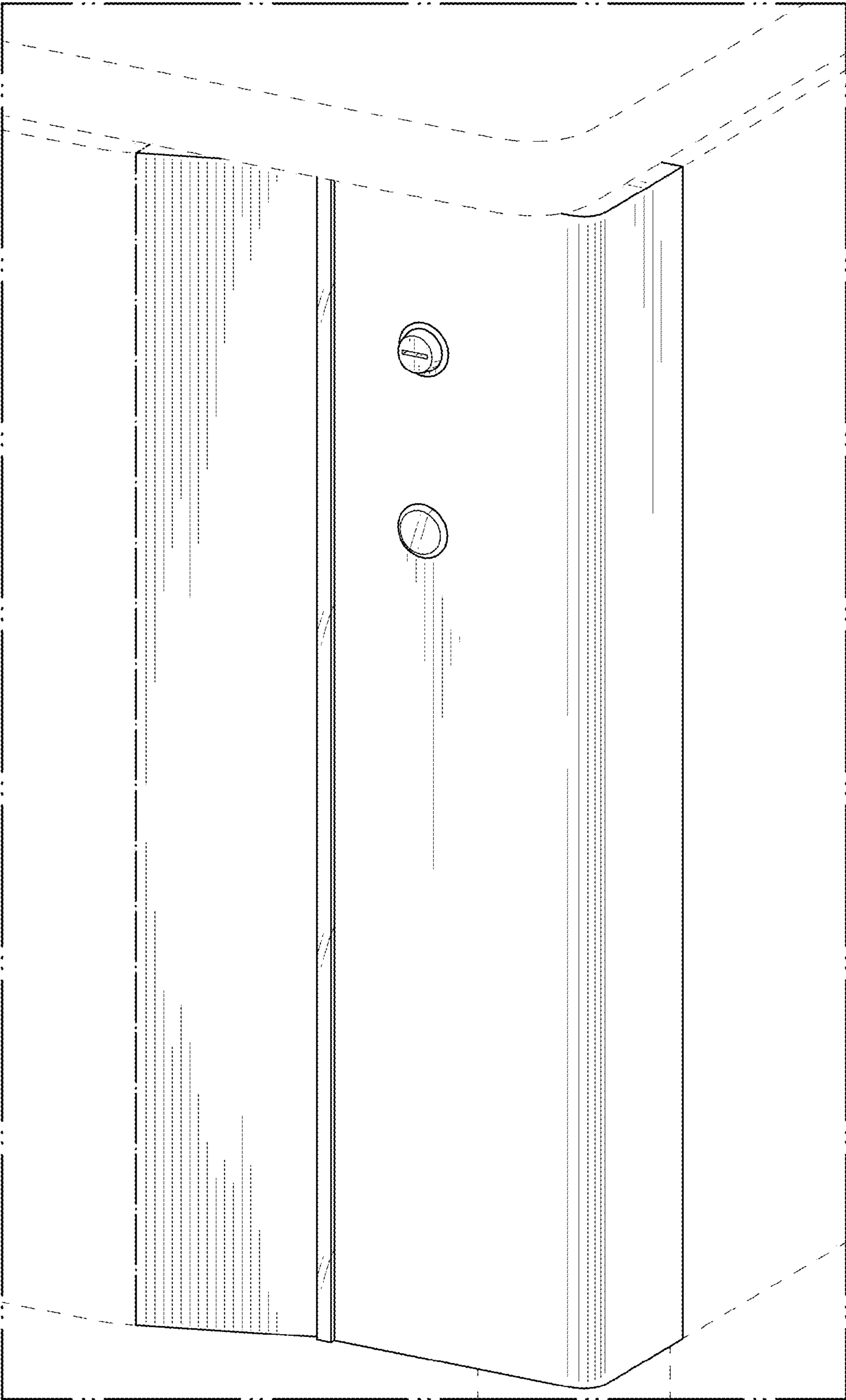


FIG. 8

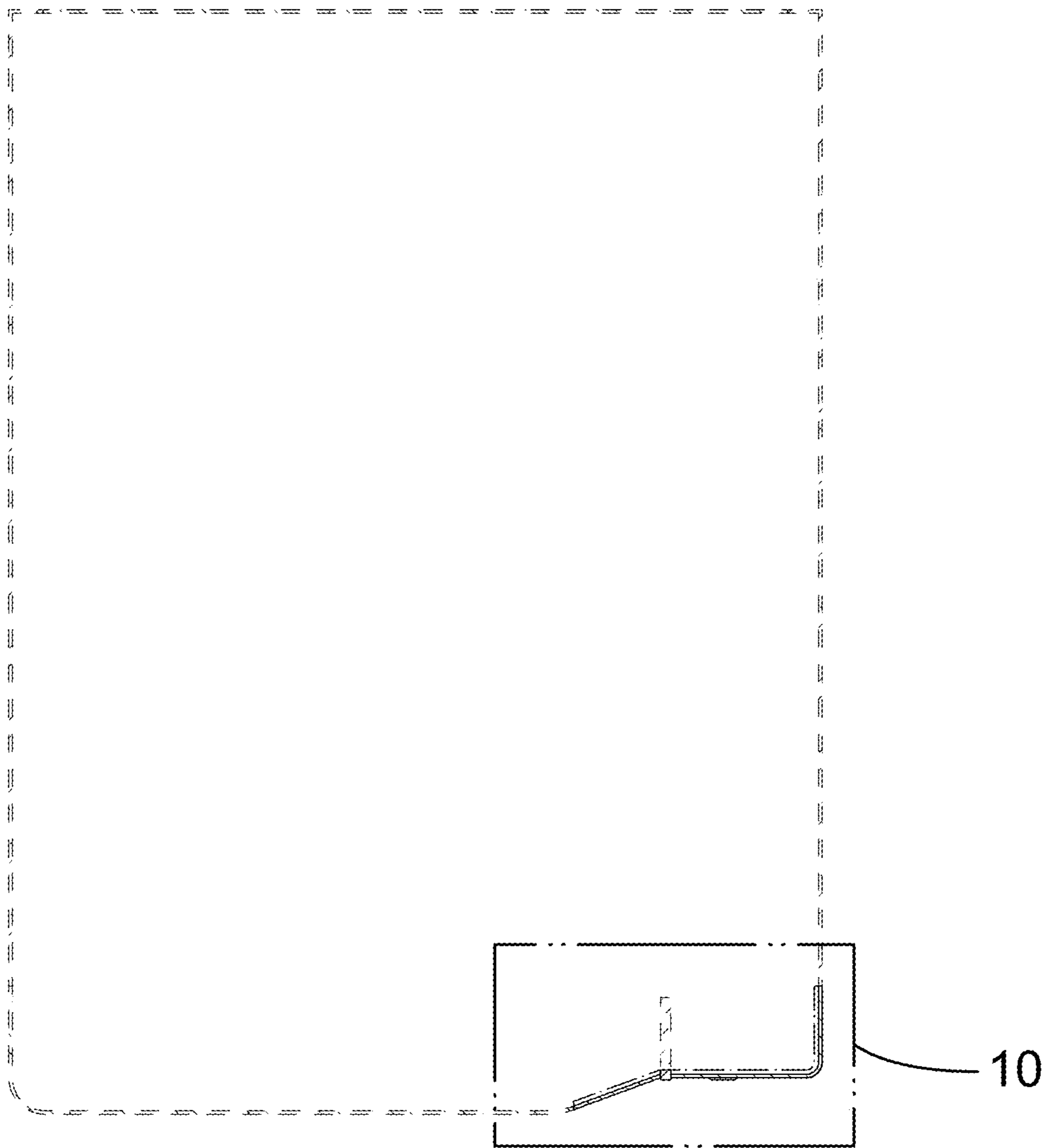


FIG. 9

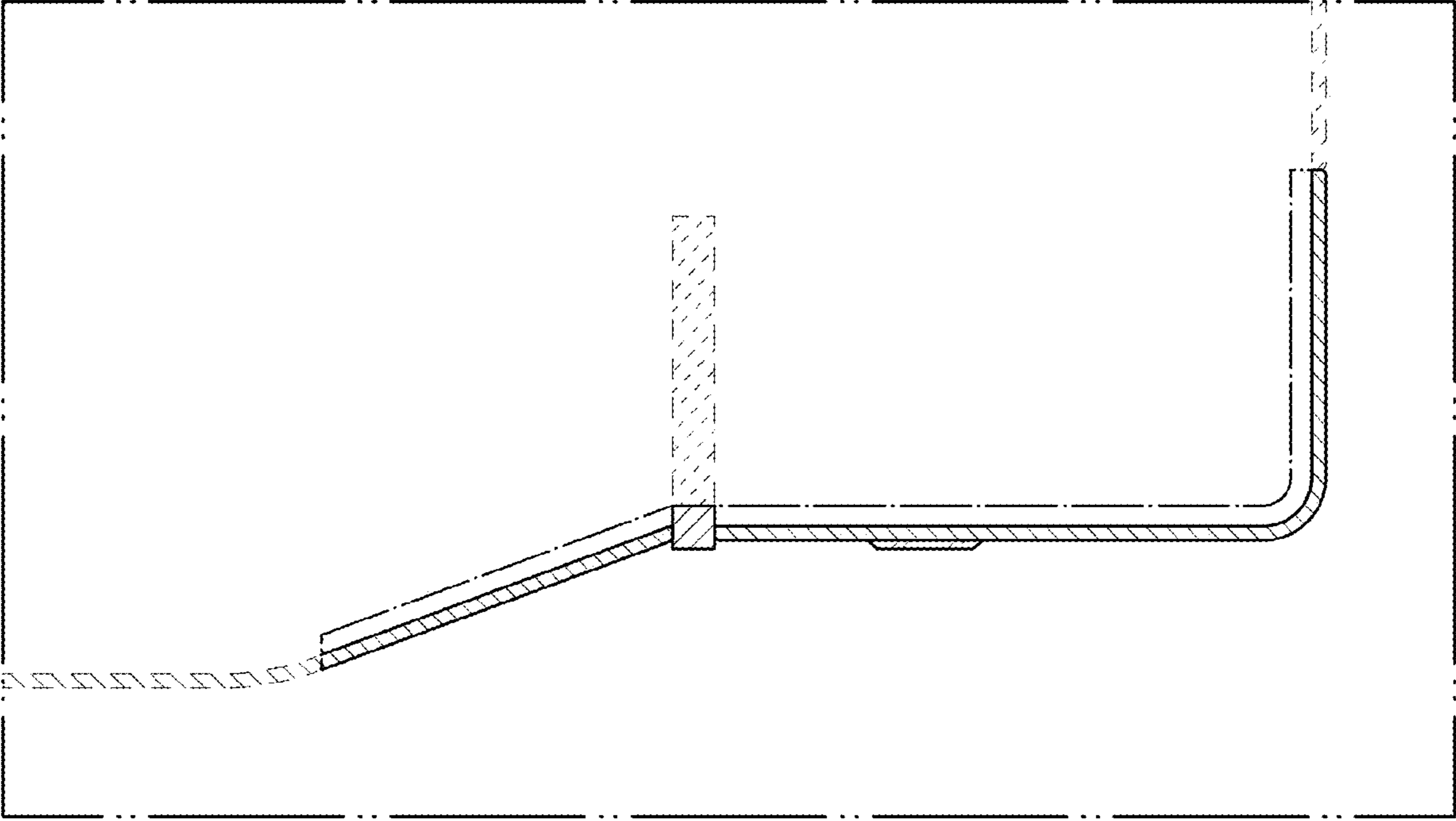


FIG. 10